

5821 THRU 5823

T.52.13.90

BiMOS II 8-BIT SERIAL-INPUT, LATCHED DRIVERS

A merged combination of bipolar and MOS technology gives these devices an interface flexibility beyond the reach of standard logic buffers and power driver arrays. The three devices in this series each have an eight-bit CMOS shift register and CMOS control circuitry, eight CMOS data latches, and eight bipolar current-sinking Darlington output drivers. Except for maximum driver output voltage ratings, the UCN5821A, UCN5822A, and UCN5823A are identical.

BiMOS II devices have much higher data-input rates than the original BiMOS circuits. With a 5 V logic supply, they will typically operate at better than 5 MHz. With a 12 V supply, significantly higher speeds are obtained. The CMOS inputs are compatible with standard CMOS and NMOS logic levels. TTL circuits may require the use of appropriate pull-up resistors. By using the serial data output, the drivers can be cascaded for interface applications requiring additional drive lines.

FEATURES

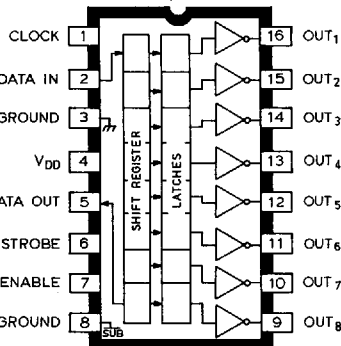
- 3.3 MHz Minimum Data Input Rate
- CMOS, NMOS, TTL Compatible
- Internal Pull-Down Resistors
- Low-Power CMOS Logic & Latches
- High-Voltage Current-Sink Outputs
- 16-Pin Dual In-Line Plastic Package

ABSOLUTE MAXIMUM RATINGS at 25°C Free-Air Temperature

Output Voltage, V_{OUT}	
(UCN5821A)	50 V
(UCN5822A)	80 V
(UCN5823A)	100 V
Logic Supply Voltage, V_{DD}	15 V
Input Voltage Range,	
V_{IN}	-0.3 V to $V_{DD} + 0.3$ V
Continuous Output Current,	
I_{OUT}	500 mA
Package Power Dissipation,	
P_D	2.08 W*
Operating Temperature Range,	
T_A	-20°C to +85°C
Storage Temperature Range,	
T_S	-55°C to +150°C

*Derate at the rate of 16.7 mW/°C above $T_A = +25^\circ\text{C}$

Caution: CMOS devices have input static protection but are susceptible to damage when exposed to extremely high static electrical charges.



Dwg. No. PP-026

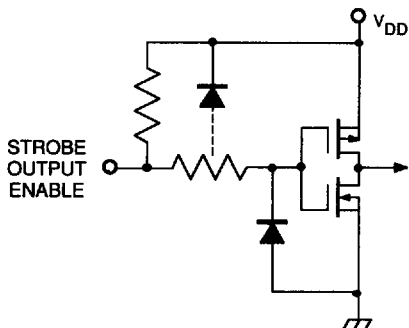
Always order by complete part number:

Part Number	Max. V_{OUT}
UCN5821A	50 V
UCN5822A	80 V
UCN5823A	100 V

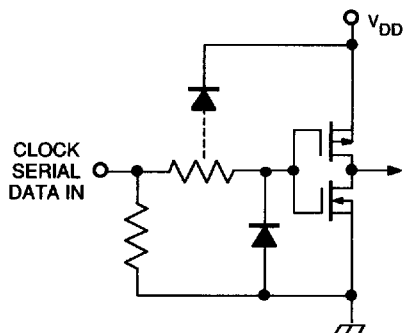
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TYPICAL INPUT CIRCUITS

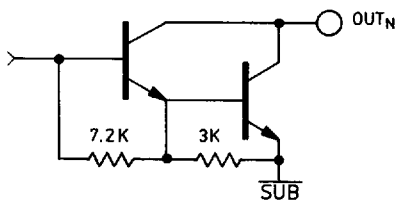


Dwg. No. EP-010-3



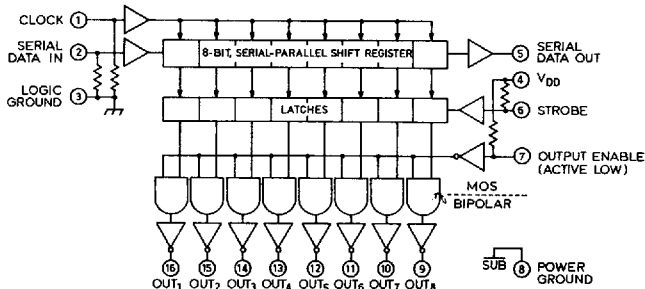
Dwg. No. EP-010-4

TYPICAL OUTPUT DRIVER



Dwg. No. A-14,314

FUNCTIONAL BLOCK DIAGRAM



Dwg. No. FP-013

Number of Outputs ON ($I_{OUT} = 200 \text{ mA}$ $V_{DD} = 12 \text{ V}$)	Max. Allowable Duty Cycle at Ambient Temperature of				
	25°C	40°C	50°C	60°C	70°C
8	90%	79%	72%	65%	57%
7	100%	90%	82%	74%	65%
6	100%	100%	96%	86%	76%
5	100%	100%	100%	100%	91%
4	100%	100%	100%	100%	100%
3	100%	100%	100%	100%	100%
2	100%	100%	100%	100%	100%
1	100%	100%	100%	100%	100%

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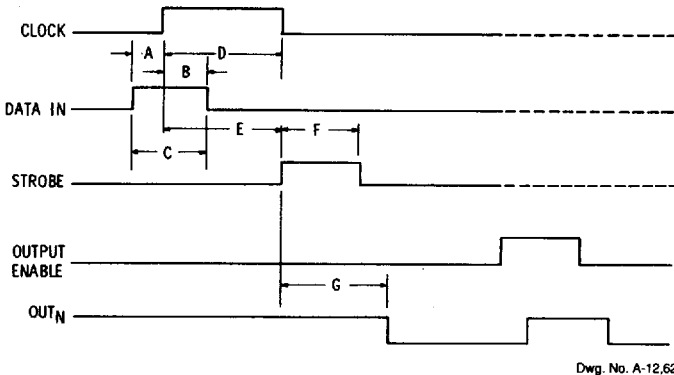
BiMOS II 8-BIT SERIAL-INPUT, LATCHED DRIVERS

ELECTRICAL CHARACTERISTICS at $T_A = +25^\circ\text{C}$, $V_{DD} = 5\text{ V}$, (unless otherwise specified).

Characteristic	Symbol	Applicable Devices	Test Conditions	Limits		
				Min.	Max.	Units
Output Leakage Current	I_{CEX}	UCN5821A	$V_{OUT} = 50\text{ V}$	—	50	μA
			$V_{OUT} = 50\text{ V}, T_A = +70^\circ\text{C}$	—	100	μA
		UCN5822A	$V_{OUT} = 80\text{ V}$	—	50	μA
			$V_{OUT} = 80\text{ V}, T_A = +70^\circ\text{C}$	—	100	μA
		UCN5823A	$V_{OUT} = 100\text{ V}$	—	50	μA
			$V_{OUT} = 100\text{ V}, T_A = +70^\circ\text{C}$	—	100	μA
Collector-Emitter Saturation Voltage	$V_{CE(SAT)}$	ALL	$I_{OUT} = 100\text{ mA}$	—	1.1	V
			$I_{OUT} = 200\text{ mA}$	—	1.3	V
			$I_{OUT} = 350\text{ mA}, V_{DD} = 7.0\text{ V}$	—	1.6	V
Input Voltage	$V_{IN(0)}$	ALL		—	0.8	V
	$V_{IN(1)}$	ALL	$V_{DD} = 12\text{ V}$	10.5	—	V
			$V_{DD} = 10\text{ V}$	8.5	—	V
		$V_{DD} = 5.0\text{ V}$	3.5	—	V	
Input Resistance	R_{IN}	ALL	$V_{DD} = 12\text{ V}$	50	—	$\text{k}\Omega$
			$V_{DD} = 10\text{ V}$	50	—	$\text{k}\Omega$
			$V_{DD} = 5.0\text{ V}$	50	—	$\text{k}\Omega$
Supply Current	$I_{DD(ON)}$	ALL	One Driver ON, $V_{DD} = 12\text{ V}$	—	4.5	mA
			One Driver ON, $V_{DD} = 10\text{ V}$	—	3.9	mA
			One Driver ON, $V_{DD} = 5.0\text{ V}$	—	2.4	mA
	$I_{DD(OFF)}$	ALL	$V_{DD} = 5.0\text{ V}$, All Drivers OFF, All Inputs = 0 V	—	1.6	mA
			$V_{DD} = 12\text{ V}$, All Drivers OFF, All Inputs = 0 V	—	2.9	mA

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BiMOS II 8-BIT SERIAL-INPUT, LATCHED DRIVERS



Dwg. No. A-12,627

TIMING CONDITIONS

($V_{DD} = 5.0 \text{ V}$, $T_A = +25^\circ\text{C}$, Logic Levels are V_{DD} and Ground)

- A. Minimum Data Active Time Before Clock Pulse (Data Set-Up Time) 75 ns
- B. Minimum Data Active Time After Clock Pulse (Data Hold Time) 75 ns
- C. Minimum Data Pulse Width 150 ns
- D. Minimum Clock Pulse Width 150 ns
- E. Minimum Time Between Clock Activation and Strobe 300 ns
- F. Minimum Strobe Pulse Width 100 ns
- G. Typical Time Between Strobe Activation and Output Transition 500 ns

Serial Data present at the input is transferred to the shift register on the logic "0" to logic "1" transition of the CLOCK input pulse. On succeeding CLOCK pulses, the registers shift data information towards the SERIAL DATA OUTPUT. The SERIAL DATA must appear at the input prior to the rising edge of the CLOCK input waveform.

Information present at any register is transferred to its respective latch when the STROBE is high (serial-to-parallel conversion). The latches will continue to accept new data as long as the STROBE is held high. Applications where the latches are bypassed (STROBE tied high) will require that the ENABLE input be high during serial data entry.

When the ENABLE input is high, all of the output buffers are disabled (OFF) without affecting the information stored in the latches or shift register. With the ENABLE input low, the outputs are controlled by the state of the latches.

TRUTH TABLE

Serial Data Input	Clock Input	Shift Register Contents						Serial Data Output	Strobe Input	Latch Contents						Output Enable	Output Contents						
		I_1	I_2	I_3	I_8	R_1			R_2	R_3	R_8	P_1	P_2		P_3	P_8	O_1	O_2	O_3
H	┌	H	R_1	R_2	R_7	R_7																
L	┐	L	R_1	R_2	R_7	R_7																
X	└	R_1	R_2	R_3	R_8	R_8																
		X	X	X	X	X	L	R_1	R_2	R_3	R_8										
		P_1	P_2	P_3	P_8	P_8	H	P_1	P_2	P_3	P_8	L									
								X	X	X	X	H									

L = Low Logic Level H = High Logic Level X = Irrelevant P = Present State R = Previous State